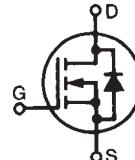


# Trench Gate Power MOSFET

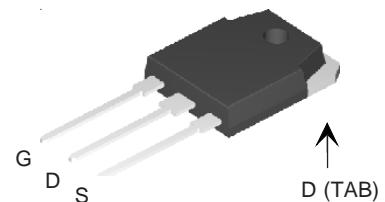
**IXTQ 50N28T**  
**IXTA 50N28T**  
**IXTP 50N28T**

$V_{DSS}$  = 280 V  
 $I_{D25}$  = 50 A  
 $R_{DS(on)}$  < 60 mΩ

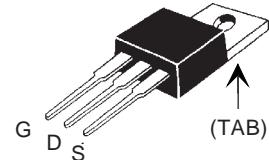
N-Channel Enhancement Mode  
For PDP drivers



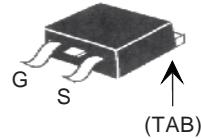
TO-3P (IXTQ)



TO-220 (IXTP)



TO-263 (IXTA)



G = Gate      D = Drain  
S = Source      TAB = Drain

Symbol	Test Conditions	Maximum Ratings		
$V_{DSS}$	$T_J = 25^\circ\text{C}$ to $175^\circ\text{C}$	280	V	
$V_{DGR}$	$T_J = 25^\circ\text{C}$ to $175^\circ\text{C}$ ; $R_{GS} = 1 \text{ M}\Omega$	280	V	
$V_{GSM}$		$\pm 30$	V	
$I_{D25}$	$T_c = 25^\circ\text{C}$	50	A	
$I_{DM}$	$T_c = 25^\circ\text{C}$ , pulse width limited by $T_{JM}$	125	A	
$P_D$	$T_c = 25^\circ\text{C}$	340	W	
$T_J$		-55 ... +150	°C	
$T_{JM}$		150	°C	
$T_{stg}$		-55 ... +150	°C	
$T_L$	1.6 mm (0.062 in.) from case for 10 s Maximum tab temperature for soldering TO-263 package for 10s	300 260	°C °C	
$M_d$	Mounting torque (TO-3P / TO-220)	1.13/10	Nm/lb.in.	
Weight	TO-3P TO-220 TO-263	5.5 4 3	g g g	

## Features

- International standard packages
- Low package inductance
  - easy to drive and to protect

## Advantages

- Easy to mount
- Space savings
- High power density

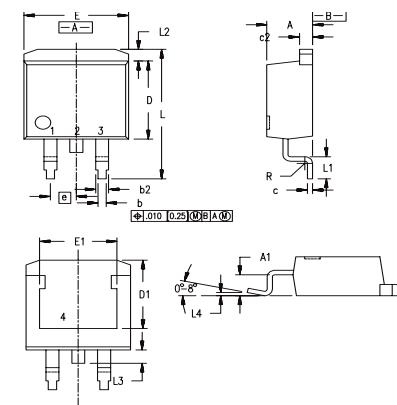
Symbol	Test Conditions ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
$V_{DSS}$	$V_{GS} = 0 \text{ V}$ , $I_D = 250 \mu\text{A}$	280		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$	2.5		4.5 V
$I_{GSS}$	$V_{GS} = \pm 20 \text{ V}_{DC}$ , $V_{DS} = 0$		$\pm 200$	nA
$I_{DSS}$	$V_{DS} = V_{DSS}$ $V_{GS} = 0 \text{ V}$		1 200	$\mu\text{A}$
$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$ , $I_D = 25 \text{ A}$ Pulse test, $t \leq 300 \mu\text{s}$ , duty cycle $d \leq 2 \%$	50	60	mΩ

**Symbol**      **Test Conditions**
**Characteristic Values**  
 $(T_J = 25^\circ\text{C}$ , unless otherwise specified)

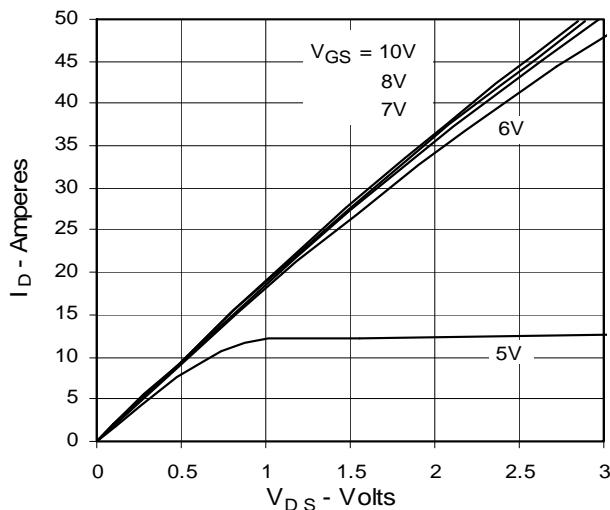
		Min.	Typ.	Max.
$g_{fs}$	$V_{DS} = 10 \text{ V}; I_D = 50 \text{ A}$ , pulse test	40	58	S
$C_{iss}$ $C_{oss}$ $C_{rss}$	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	4070	pF	
		405	pF	
		24	pF	
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$	$V_{GS} = 10 \text{ V}, V_{DS} = 140 \text{ V}, I_D = 25 \text{ A}$ $R_G = 5 \Omega$ (External)	37	ns	
		31	ns	
		68	ns	
		36	ns	
$Q_{g(on)}$ $Q_{gs}$ $Q_{gd}$	$V_{GS} = 10 \text{ V}, V_{DS} = 140 \text{ V}, I_D = 25 \text{ A}$	87	nC	
		32	nC	
		25	nC	
$R_{thJC}$			0.37 K/W	
$R_{thCK}$	(TO-3P)	0.21	K/W	
	(TO-220)	0.25	K/W	

**Source-Drain Diode**
**Characteristic Values**  
 $(T_J = 25^\circ\text{C}$ , unless otherwise specified)

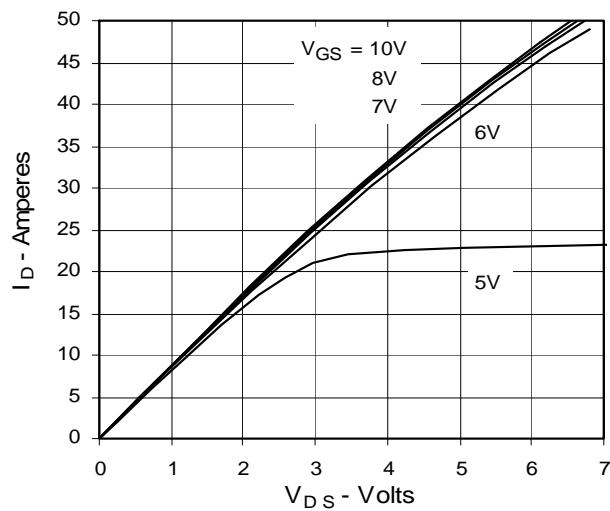
	Test Conditions	Min.	typ.	Max.
$I_s$	$V_{GS} = 0 \text{ V}$			50 A
$I_{SM}$	Repetitive			120 A
$V_{SD}$	$I_F = 50 \text{ A}, V_{GS} = 0 \text{ V}$ , Pulse test, $t \leq 300 \mu\text{s}$ , duty cycle $d \leq 2 \%$			1.5 V
$t_{rr}$	$I_F = 25 \text{ A}$ $-di/dt = 100 \text{ A}/\mu\text{s}$	180	ns	
$Q_{RM}$	$V_R = 25 \text{ V}$		1.3	$\mu\text{C}$

**TO-263 (IXTA) Outline**


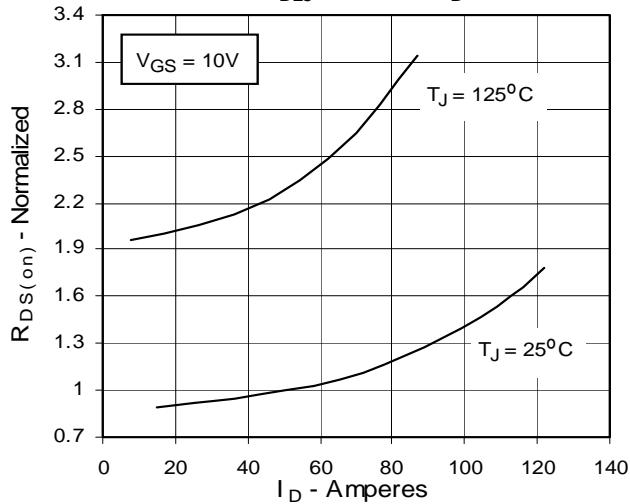
**Fig. 1. Output Characteristics  
@ 25°C**



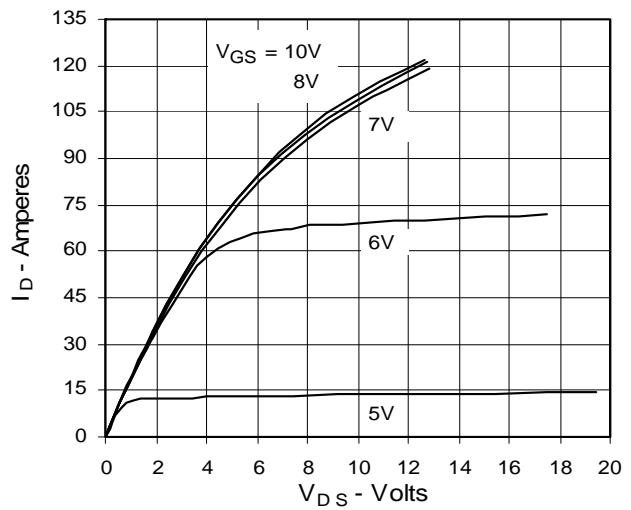
**Fig. 3. Output Characteristics  
@ 125°C**



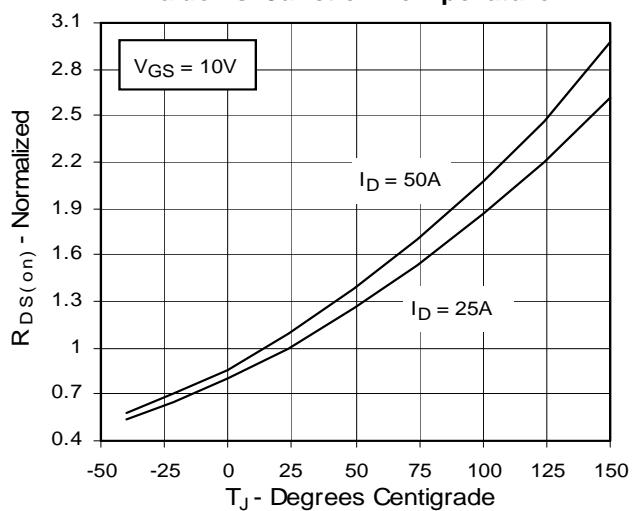
**Fig. 5.  $R_{DS(on)}$  Normalized to  
0.5  $I_{D25}$  Value vs.  $I_D$**



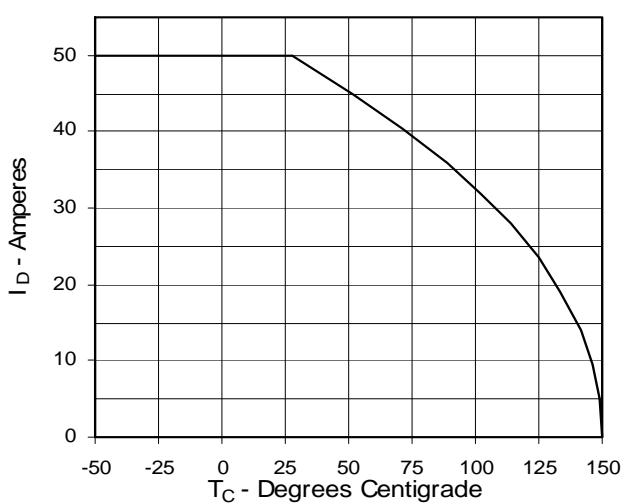
**Fig. 2. Extended Output Characteristics  
@ 25°C**

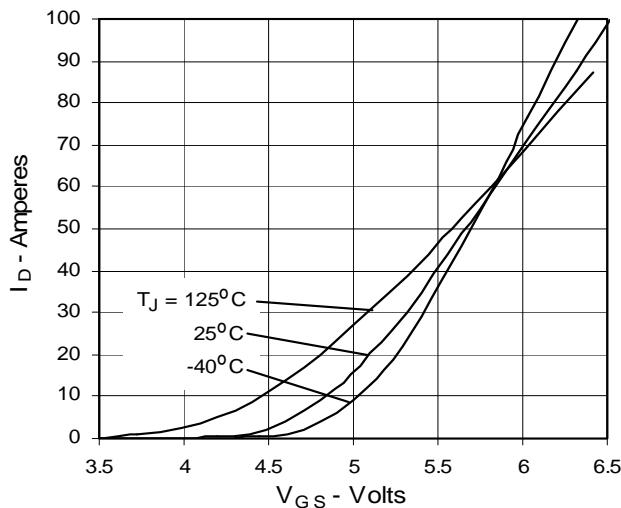
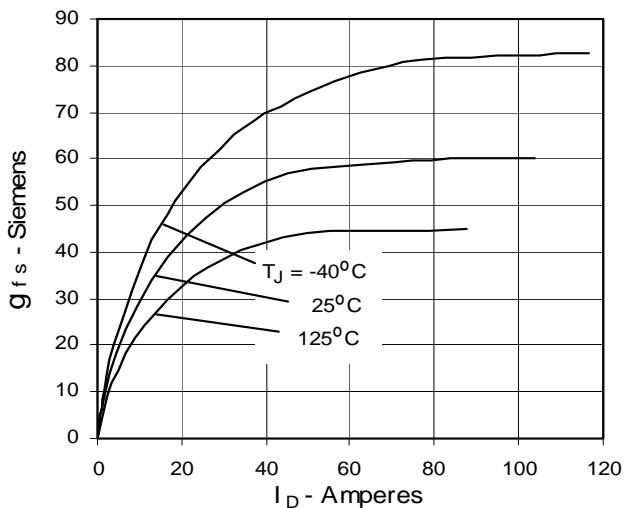
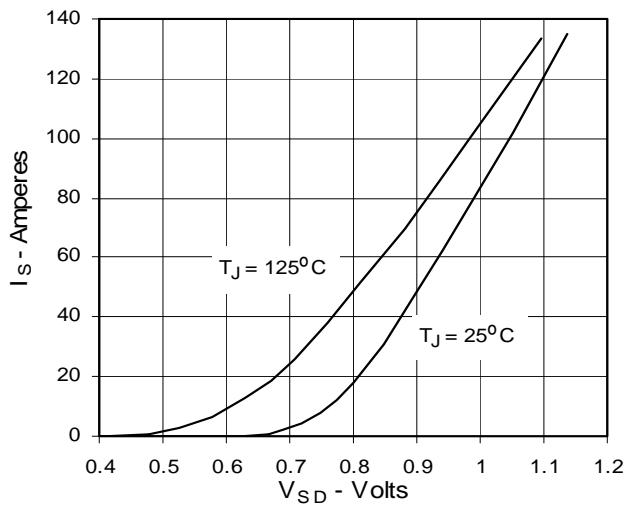
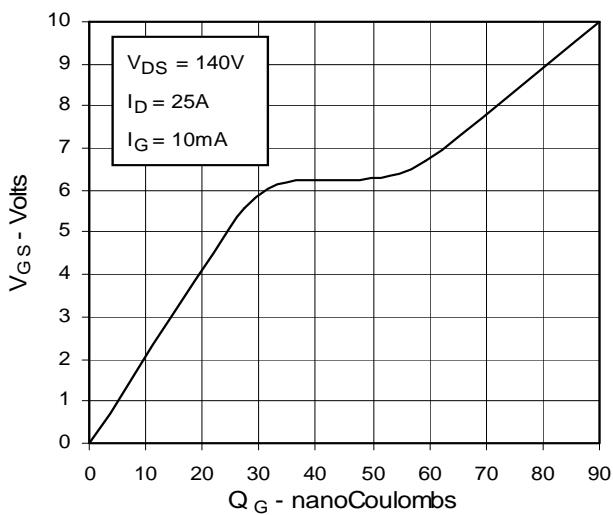
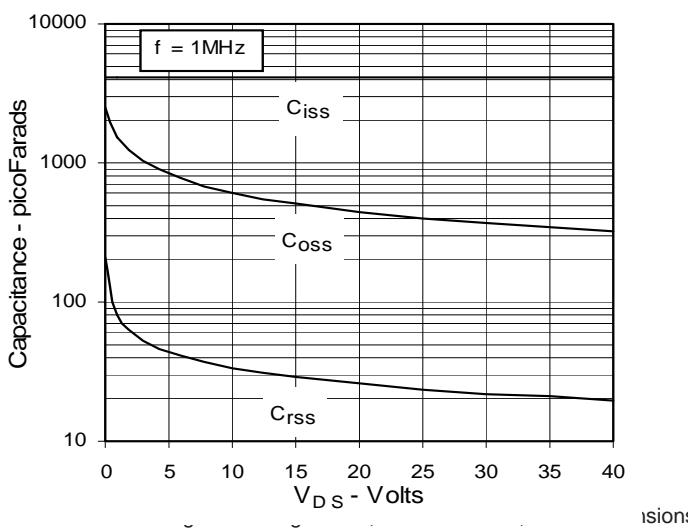
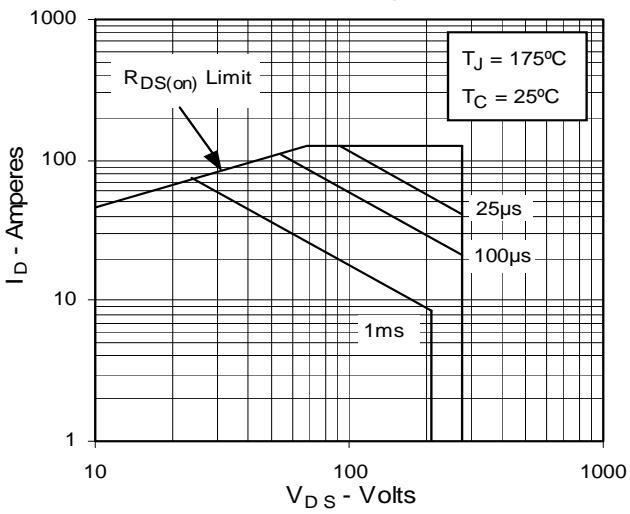


**Fig. 4.  $R_{DS(on)}$  Normalized to 0.5  $I_{D25}$   
Value vs. Junction Temperature**



**Fig. 6. Drain Current vs. Case  
Temperature**



**Fig. 7. Input Admittance**

**Fig. 8. Transconductance**

**Fig. 9. Source Current vs. Source-To-Drain Voltage**

**Fig. 10. Gate Charge**

**Fig. 11. Capacitance**

**Fig. 12. Forward-Bias Safe Operating Area**


**Fig. 13. Maximum Transient Thermal Resistance**